

V.2. Signal Acquisition

- Determine energy deposited in detector
- Detector signal generally a short current pulse

Typical durations

Thin silicon detector (10 ... 300 μm thick):	100 ps – 30 ns
Thick ($\sim\text{cm}$) Si or Ge detector:	1 – 10 μs
Proportional chamber (gas):	10 ns – 10 μs
Gas microstrip or microgap chamber:	10 – 50 ns
Scintillator + PMT/APD:	100 ps – 10 μs

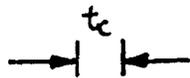
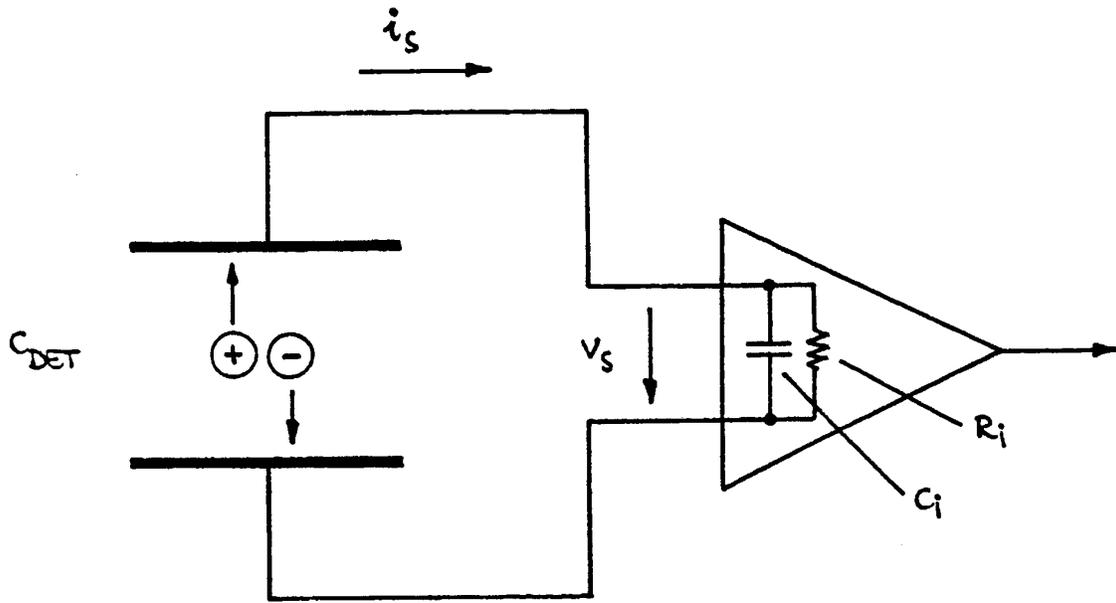
The total charge Q_s contained in the detector current pulse is $i_s(t)$ proportional to the energy deposited in the detector

$$E \propto Q_s = \int i_s(t) dt$$

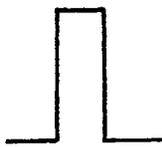
- Necessary to integrate the detector signal current.

- Possibilities:
1. Integrate charge on input capacitance
 2. Use integrating (“charge sensitive”) preamplifier
 3. Amplify current pulse and use integrating (“charge sensing”) ADC

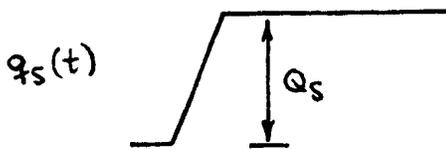
Signal integration on Input Capacitance



$i_s(t)$



$R_i \cdot (C_{DET} + C_i) \gg \text{COLLECTION TIME } t_c$



$$\rightarrow V_s = \frac{Q_s}{C_{DET} + C_i}$$



System response depends on detector capacitance !

Detector capacitance may vary within a system or change with bias voltage (partially depleted semiconductor diode).

⇒ make system whose gain (dV_{out}/dQ_s) is independent of detector capacitance.

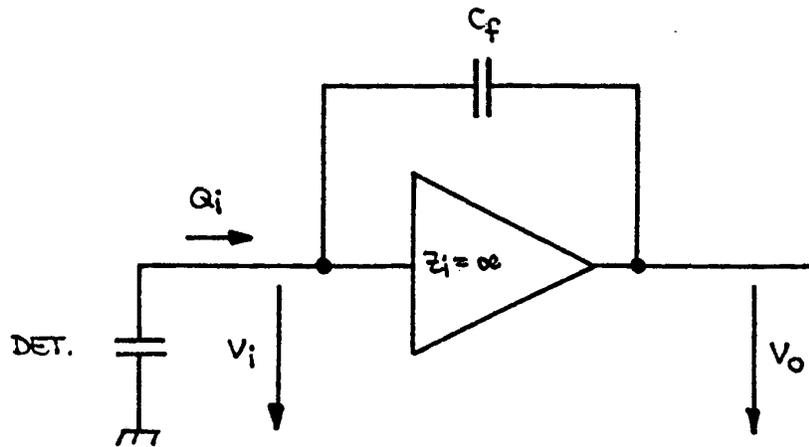
Active Integrator (“charge-sensitive amplifier”)

Start with inverting voltage amplifier

Voltage gain $dV_o/dV_i = -A \Rightarrow v_o = -A v_i$

Input impedance = ∞ (i.e. no signal current flows into amplifier input)

Connect feedback capacitor C_f between output and input.



Voltage difference across C_f : $v_f = (A+1) v_i$

\Rightarrow Charge deposited on C_f : $Q_f = C_f v_f = C_f (A+1) v_i$

$Q_i = Q_f$ (since $Z_i = \infty$)

\Rightarrow Effective input capacitance

$$C_i = \frac{Q_i}{v_i} = C_f (A+1)$$

(“dynamic” input capacitance)

Gain

$$A_Q = \frac{dV_o}{dQ_i} = \frac{A \cdot v_i}{C_i \cdot v_i} = \frac{A}{C_i} = \frac{A}{A+1} \cdot \frac{1}{C_f} \approx \frac{1}{C_f} \quad (A \gg 1)$$

Q_i is the charge flowing into the preamplifier

but some charge remains on C_{det} .

What fraction of the signal charge is measured?

$$\begin{aligned}\frac{Q_i}{Q_s} &= \frac{C_i v_i}{Q_{det} + Q_i} = \frac{C_i}{Q_s} \cdot \frac{Q_s}{C_i + C_{det}} \\ &= \frac{1}{1 + \frac{C_{det}}{C_i}} \approx 1 \quad (\text{if } C_i \gg C_{det})\end{aligned}$$

Example:

$$A = 10^3$$

$$C_f = 1 \text{ pF} \quad \Rightarrow \quad C_i = 1 \text{ nF}$$

$$C_{det} = 10 \text{ pF}: \quad Q_i/Q_s = 0.99$$

$$C_{det} = 500 \text{ pF}: \quad Q_i/Q_s = 0.67$$



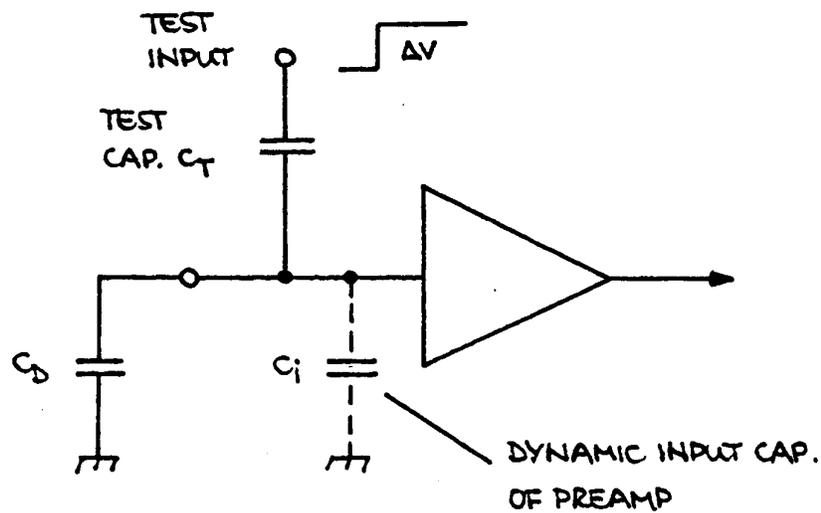
Si Det.: 50 μm thick
500 mm^2 area

Note: Input coupling capacitor must be $\gg C_i$ for high charge transfer efficiency.

Calibration

Inject specific quantity of charge - measure system response

Use voltage pulse (can be measured conveniently with oscilloscope)



$C_i \gg C_T \Rightarrow$ Voltage step applied to test input develops over C_T .

$$\Rightarrow Q_T = \Delta V \cdot C_T$$

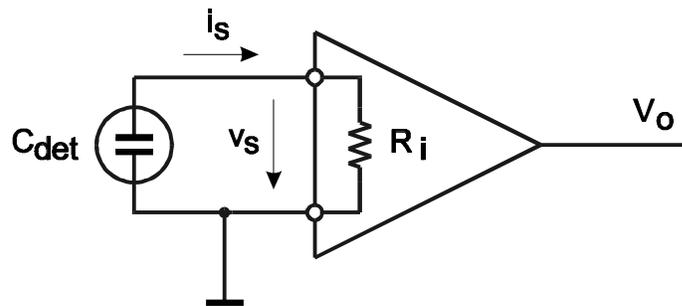
Accurate expression:

$$Q_T = \frac{C_T}{1 + \frac{C_T}{C_i}} \cdot \Delta V \approx C_T \left(1 - \frac{C_T}{C_i} \right) \Delta V$$

Typically: $C_T/C_i = 10^{-3} - 10^{-4}$

Summary of Amplifier Types

1. Simple Amplifiers



Output voltage $V_o = \text{voltage gain } A_v \times \text{input voltage } v_s$.

Operating mode depends on charge collection time t_{coll} and the input time constant $R_i C_{det}$:

a) $R_i C_{det} \ll t_{coll}$ detector capacitance discharges rapidly

$$\Rightarrow V_o \propto i_s(t)$$

current sensitive amplifier

b) $R_i C_{det} \gg t_{coll}$ detector capacitance discharges slowly

$$\Rightarrow V_o \propto \int i_s(t) dt$$

voltage sensitive amplifier

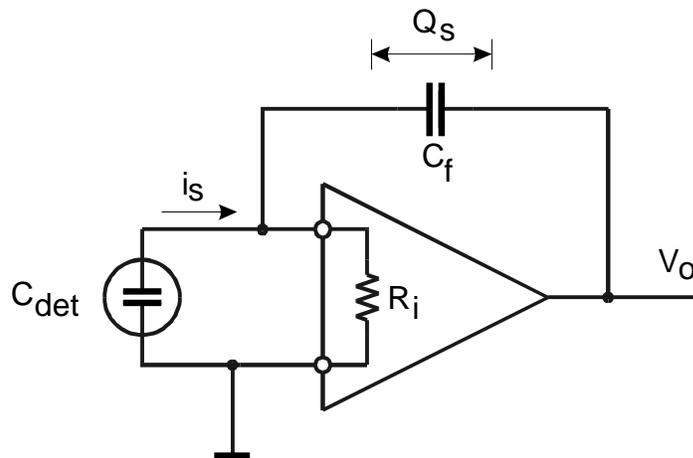
In both cases the output signal voltage is determined directly by the input voltage.

2. Feedback Amplifiers

Basic amplifier as used above.

High input resistance: $R_i C_{det} \gg t_{coll}$

Add feedback capacitance C_f



Signal current i_s is integrated on feedback capacitor C_f :

$$V_o \propto Q_s / C_f$$

Amplifier output directly determined by signal charge,
insensitive to detector capacitance

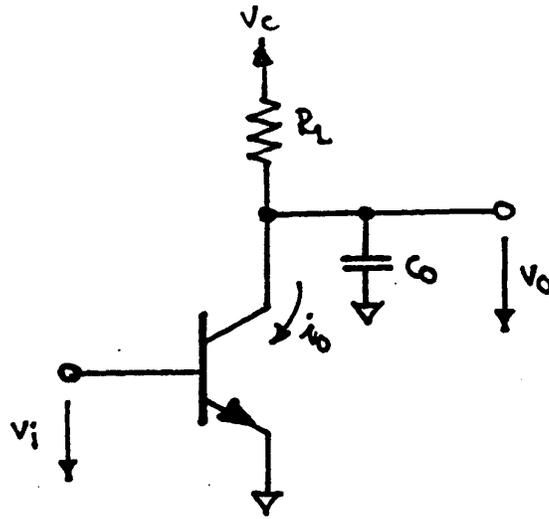
⇒ charge-sensitive amplifier

Realistic Charge-Sensitive Preamplifiers

The preceding discussion assumed idealized amplifiers with infinite speed.

- How do “real” amplifiers affect charge response?
- How does the detector affect amplifier response?

A Simple Amplifier



Voltage gain:

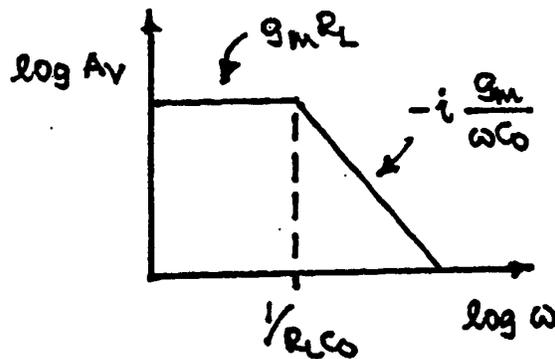
$$A_V = \frac{dv_o}{dv_i} = \frac{di_o}{dv_i} \cdot Z_L \equiv g_m Z_L$$

$g_m \equiv$ transconductance

$$Z_L = R_L // C_o$$

$$\frac{1}{Z_L} = \frac{1}{R_L} + i\omega C_o \quad \Rightarrow \quad A_V = g_m \left(\frac{1}{R_L} + i\omega C_o \right)^{-1}$$

\uparrow low freq. \uparrow high freq.



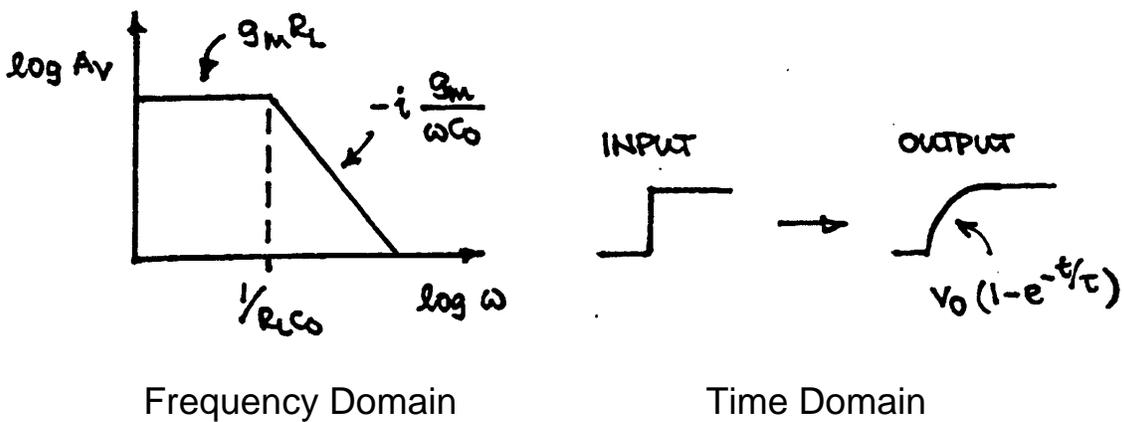
\uparrow upper cutoff frequency $2\pi f_u$

Pulse Response of the Simple Amplifier

A voltage step $v_i(t)$ at the input causes a current step $i_o(t)$ at the output of the transistor.

For the output voltage to change, the stray capacitance C_o must first charge up.

⇒ The output voltage changes with a time constant $\tau = R_L C_o$



Note that τ is the inverse upper cutoff frequency $1/(2\pi f_u)$

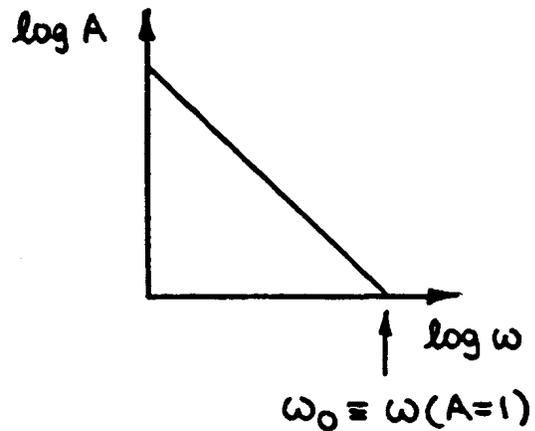
Input Impedance of a Charge-Sensitive Amplifier

Input impedance

$$Z_i = \frac{Z_f}{A+1} \approx \frac{Z_f}{A} \quad (A \gg 1)$$

Amplifier gain vs. frequency

$$A = -i \frac{\omega_0}{\omega}$$



Gain-Bandwidth Product

Feedback Impedance

$$Z_f = -i \frac{1}{\omega C_f}$$

⇒ Input Impedance

$$Z_i = -\frac{i}{\omega C_f} \cdot \frac{1}{-i \frac{\omega}{\omega_0}}$$

$$Z_i = \frac{1}{\omega_0 C_f}$$

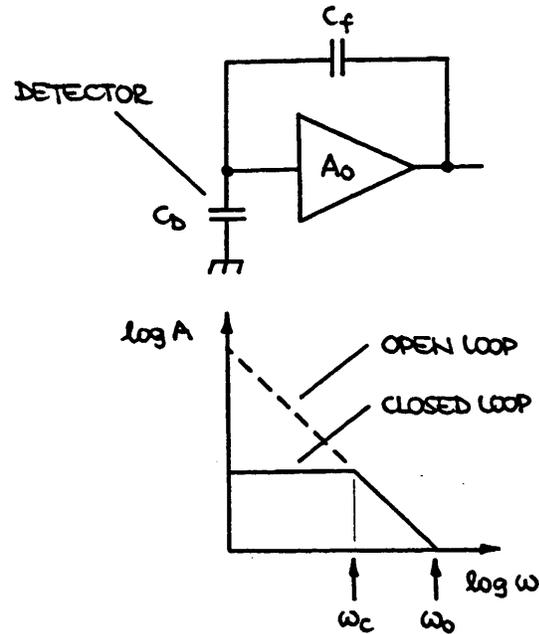
Imaginary component vanishes ⇒ *Resistance: $Z_i \rightarrow R_i$*

Time Response of a Charge-Sensitive Amplifier

Closed Loop Gain

$$A_f = \frac{C_D + C_f}{C_f} \quad (A_f \ll A_0)$$

$$A_f \approx \frac{C_D}{C_f} \quad (C_D \gg C_f)$$



Closed Loop Bandwidth

$$\omega_c A_f = \omega_0$$

Response Time

$$\tau_{amp} = \frac{1}{\omega_c} = C_D \frac{1}{\omega_0 C_f}$$

Alternative Picture: Input Time Constant

$$\tau_i = R_i C_D$$

$$\tau_i = \frac{1}{\omega_0 C_f} \cdot C_D = \tau_{amp}$$

Same result as from conventional feedback theory.